



Programme

The Society of Electron Microscope Technology

One Day Meeting at The Natural History Museum 20th June 2008

- 09.15am. **Registration, Tea/Coffee**
- 10.00am **Alex Ball, NHM**
Introduction and welcome
- 10.15am. **Anton Kearsley, NHM**
The first cometary and interstellar particles returned to Earth: using SEM to find and analyse impact craters on the Stardust spacecraft.
- 10.45am. **Stewart Bean, Zeiss SMT**
Imaging and microanalysis in the variable pressure SEM
- 11.05am. **Coffee break and refreshments – trade exhibition**
- 11.40am **Chris Jones, Hitachi**
Tabletop to Field Emission - Variable Pressure SEM to suit all needs
- 12.00pm **Nigel Meeks, British Museum**
VPSEM at the British Museum
- 12.25pm **Neil Wilkinson, Gatan**
New 3-D microscopies in VP-SEM
- 12.45pm **Lunch break and trade exhibition, opportunity to tour EMMA lab facilities**
- 14.10pm **Steve Pitman, ERA**
Using VPSEM in electrical failure investigations
- 14.40pm. **Marc Schmidt, Laser Processing Research Centre
The University of Manchester**
SEM imaging of high volume laser fabricated Ni and Ag nanoparticles
- 15.05pm **Spike Bucklow, Cambridge University**
Scanning Electron Microscopy at the Hamilton Kerr Institute
- 15.30pm **Afternoon coffee break and refreshments – trade exhibition**
- 16.20pm **Ronaldo Ronaldo, Precision Manufacturing Centre -
The University of Nottingham**
The role of SEM in precision manufacturing
- 16.45pm **Chris Walker, JEOL**
Product line overview
- 17.10pm **Meeting close - Retire to pub...?**

Sponsorship for the meeting has kindly been provided by



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